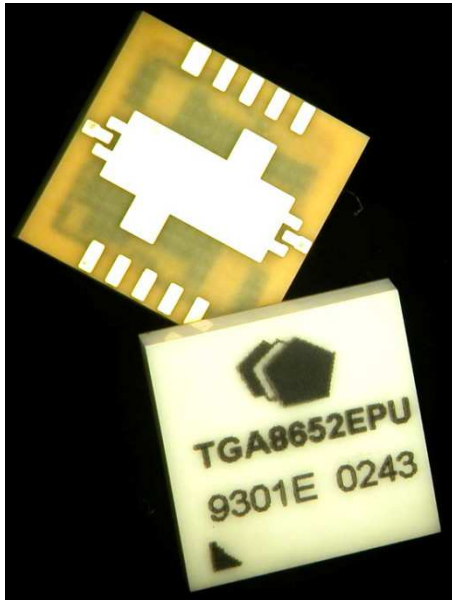


## 9.9-12.5Gb/s Optical Modulator Driver

## TGA8652-SL

OC-192 Metro and Long Haul Applications  
Surface Mount Package



### Description

The TriQuint TGA8652-SL is a medium power wideband AGC amplifier combined with off chip circuitry assembled in a Surface Mount Package. The TGA8652-SL typically provides 16dB small signal gain with 6dB AGC range. Typical input and output return loss is <10dB. Typical Noise Figure is 2.5dB at 3GHz. Typical saturated output power is 25dBm. Small signal 3dB BW is 12GHz with saturated power performance to 16GHz. RF ports are DC coupled enabling the user to customize system corner frequencies. Applications include OC192 12.5Gbit/s NRZ MZ Modulator Driver and receive AGC amplifier.

Drain bias may be applied thru the on-chip drain termination resistor for low drive applications or thru the RF output port for high drive applications. A cascaded pair demonstrated 8Vpp output voltage swing with 500mVpp at the input when stimulated with 10Gbit/s. 2<sup>31</sup>-1prbs. NRZ data.

The TGA8652-SL is available on an evaluation board.

### Key Features and Performance

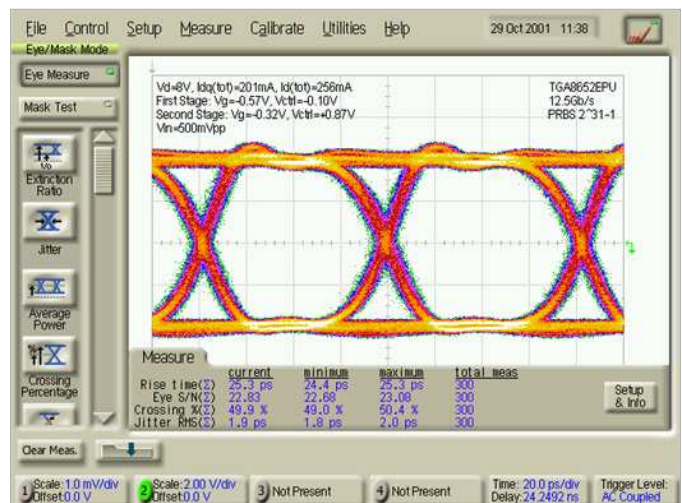
- DC - 12 GHz Linear BW
- DC - 16 GHz Saturated Power BW
- 16 dB small signal gain
- Wide Drive Range (4V to 8V)
- 25 ps Edge Rates (10/90)
- Low Power Dissipation (1.4W at Vo=8V)
- Package size: .350 x .350 x .084 inches.
- Evaluation Board Available.

### Primary Applications

- Mach-Zehnder Modulator Driver
- Pre-Driver
- Receiver AGC

### Measured Performance

Cascaded 8652 Evaluation Boards  
12.5 Gb/s Performance  
Output = 8 Vpp, Input = 500 mVpp  
Scale: 2 V/div, 20 ps/div



Note: Datasheet is subject to change without notice.

**MAXIMUM RATINGS**

SYMBOL	PARAMETER <u>1/</u>	VALUE	NOTES
V <sup>+</sup> Vd(RFout)	POSITIVE SUPPLY VOLTAGE		
	Drain bias applied thru on-chip termination	12 V	
	Drain bias applied at RF output using bias T	10 V	
V <sup>+</sup> Id	POSITIVE SUPPLY CURRENT		
	Drain bias applied thru on-chip termination	110 mA	<u>2/</u>
	Drain bias applied at RF output using bias T	250 mA	
P <sub>d</sub>	POWER DISSIPATION	2.4 W	<u>3/</u>
V <sub>g</sub> I <sub>g</sub>	NEGATIVE GATE		
	Voltage	0 V to -3 V	
	Gate Current	5 mA	
V <sub>ctrl</sub> I <sub>ctrl</sub>	CONTROL GATE		
	Voltage	Vd/2 to -3 V	<u>4/</u>
	Gate Current	5 mA	
P <sub>IN</sub>	RF INPUT		
	Sinusoidal Continuous Wave Power	23 dBm	
T <sub>CH</sub>	OPERATING CHANNEL TEMPERATURE	200 °C	<u>5/ 6/</u>
T <sub>STG</sub>	STORAGE TEMPERATURE	-40 to 125 °C	

**Notes:**

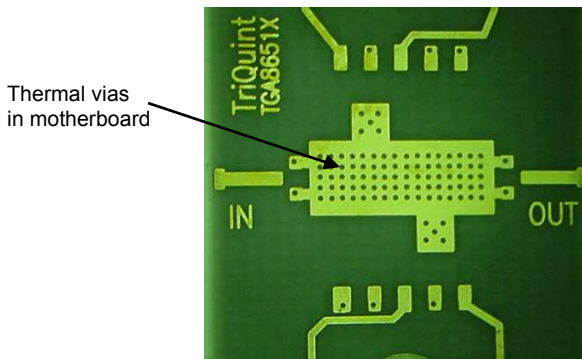
- 1/ These ratings represent the maximum operable values for the device.
- 2/ Assure the combination of Vd and Id does not exceed maximum power dissipation rating.
- 3/ When operated at this bias condition with a base plate temperature of 80 °C, the Median Lifetime (Tm) is 1E+6 hours.
- 4/ Assure Vctrl never exceeds Vd during bias on and off sequences, and normal operation.
- 5/ These ratings apply to each individual FET.
- 6/ Junction operating temperature will directly affect the device lifetime. For maximum life, it is recommended that junction temperatures be maintained at the lowest possible levels.

**THERMAL INFORMATION\***

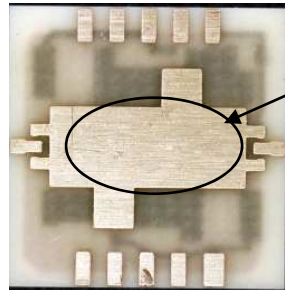
Parameter	Test Condition	T <sub>CH</sub> (°C)	R <sub>θJC</sub> (°C/W)	MTTF (HRS)
R <sub>θJC</sub> Thermal Resistance (channel to backside of package)	Vd(RF out) = 6.5 V, Vctrl = 1 V, Id = 170 mA ± 5%, T <sub>base</sub> = 80 °C	114.70	31.40	2.6E+7

NOTE: Thermal transfer is conducted thru the bottom of the TGA8652-SL package into the motherboard. Design the motherboard to assure adequate thermal transfer to the base plate. An array of filled thermal vias is recommended as shown in the example below.

\* This information is a result of a thermal model.



Motherboard



Bottom View TGA8652-SL

**RF SPECIFICATIONS**

(T<sub>A</sub> = 25°C Nominal)

NOTE	TEST	MEASUREMENT CONDITIONS	VALUE			UNITS
			MIN	TYP	MAX	
	SMALL SIGNAL BW			12		GHz
	SATURATED POWER BW			16		GHz
<u>1/</u> , <u>2/</u>	SMALL-SIGNAL GAIN MAGNITUDE	2 and 4 GHz 6 GHz 10 GHz 14 GHz 16 GHz	15 13 13 10 10	16 15 14 13 13		dB
	SMALL SIGNAL AGC RANGE	Midband		15		dB
<u>1/</u> , <u>2/</u>	INPUT RETURN LOSS MAGNITUDE	2, 4, 6, and 10 GHz 14 and 18 GHz	9 8	10 10		dB
<u>1/</u> , <u>2/</u>	OUTPUT RETURN LOSS MAGNITUDE	2, 4, 6, and 10 GHz 14 and 18 GHz	10 8	10 10		dB
<u>6/</u> , <u>7/</u>	SATURATED OUTPUT POWER	2, 4, 6, 8, and 10 GHz	25			dBm
<u>3/</u> , <u>4/</u>	EYE AMPLITUDE	V <sub>d</sub> (RF <sub>out</sub> ) = 7 V V <sub>d</sub> (RF <sub>out</sub> ) = 6 V V <sub>d</sub> (RF <sub>out</sub> ) = 5 V V <sub>d</sub> (RF <sub>out</sub> ) = 4.5 V	8.0 7.0 6.0 5.5			V <sub>pp</sub>
<u>3/</u> , <u>4/</u> , <u>5/</u>	ADDITIVE JITTER (p-p)			5		ps
<u>3/</u> , <u>4/</u>	RISE TIME (10/90)			25		ps

**Notes:**

1/ Verified at package level RF probe.

2/ Package Probe Bias: V<sup>+</sup> = 8 V, adjust Vg1 to achieve I<sub>d</sub> = 87 mA, V<sub>ctrl</sub> = +1 V

3/ Verified by design, TGA8652-SL assembled onto a demonstration board shown on page 7 then tested using the application circuit and bias procedure detailed on pages 8 and 9.

4/ V<sub>in</sub> = 2 V, Data Rate = 12.5 Gb/s, V<sub>ctrl</sub> and Vg are adjusted for maximum output.

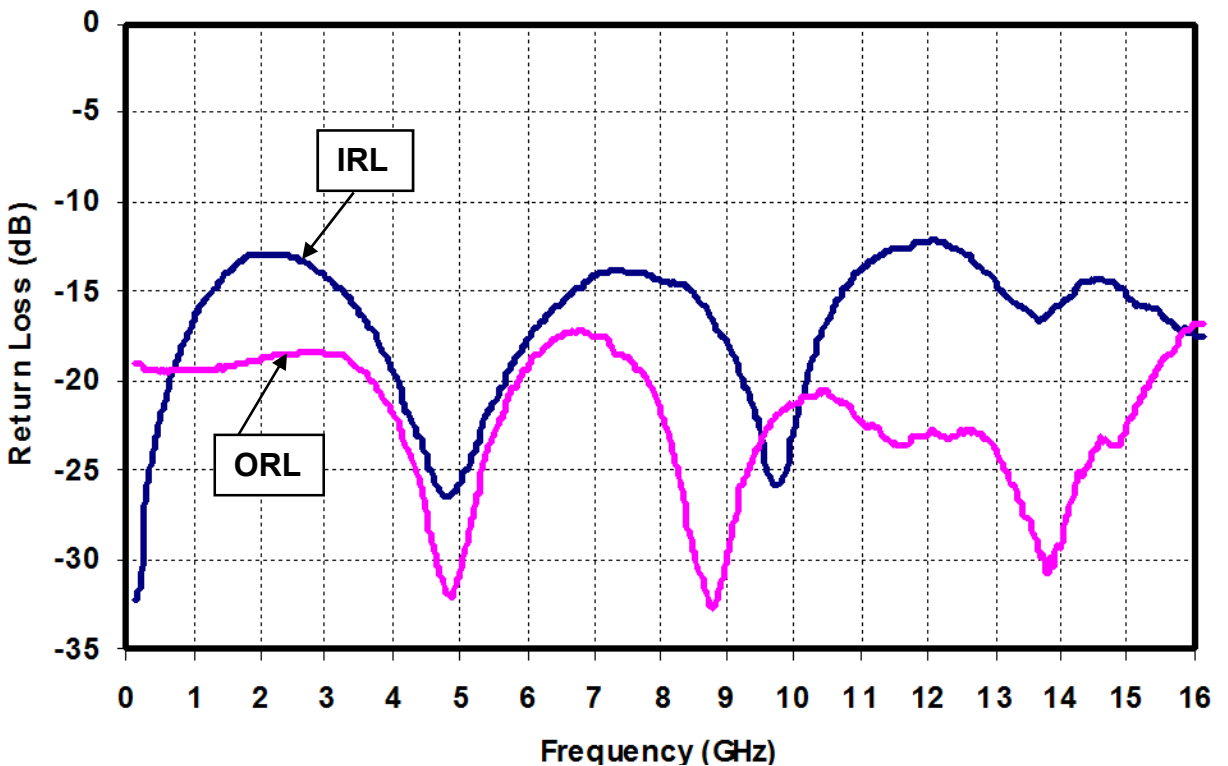
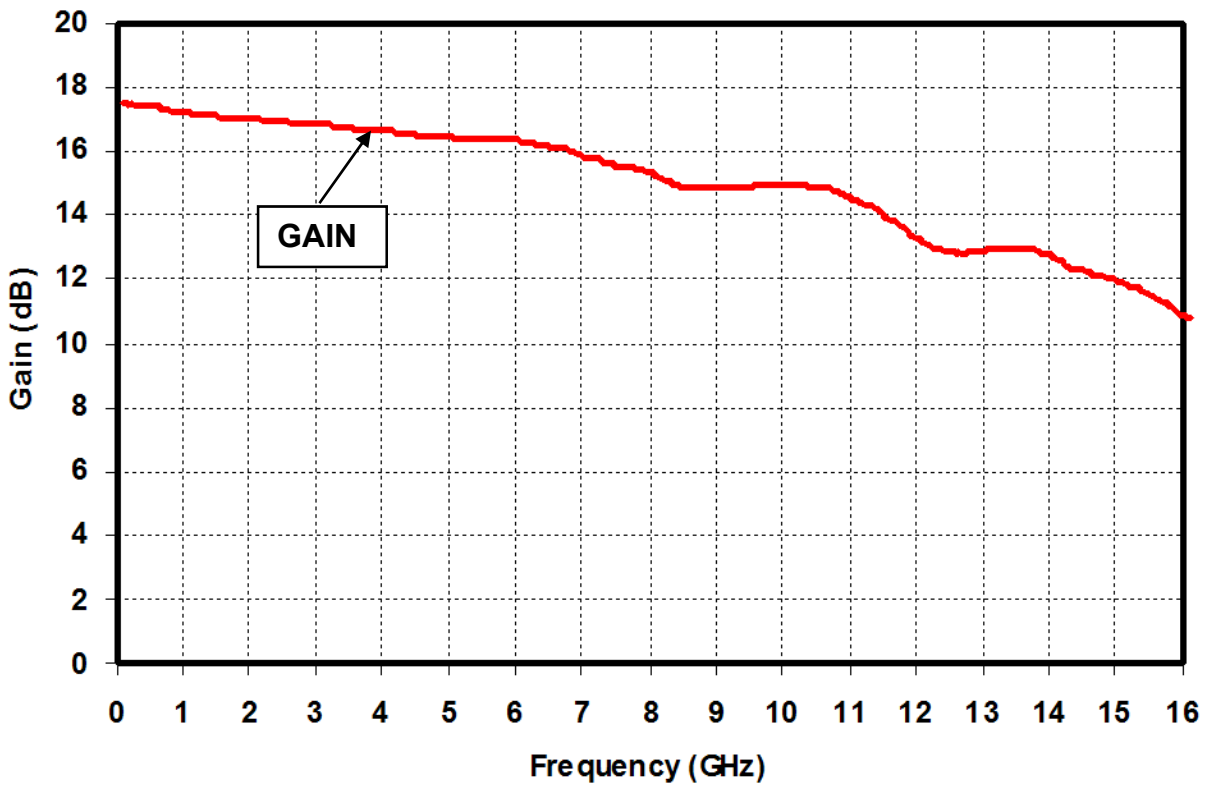
5/ Computed using RSS Method where J<sub>pp\_additive</sub> = SQRT(J<sub>pp\_out</sub><sup>2</sup> - J<sub>pp\_in</sub><sup>2</sup>)

6/ Verified at die level on-wafer probe.

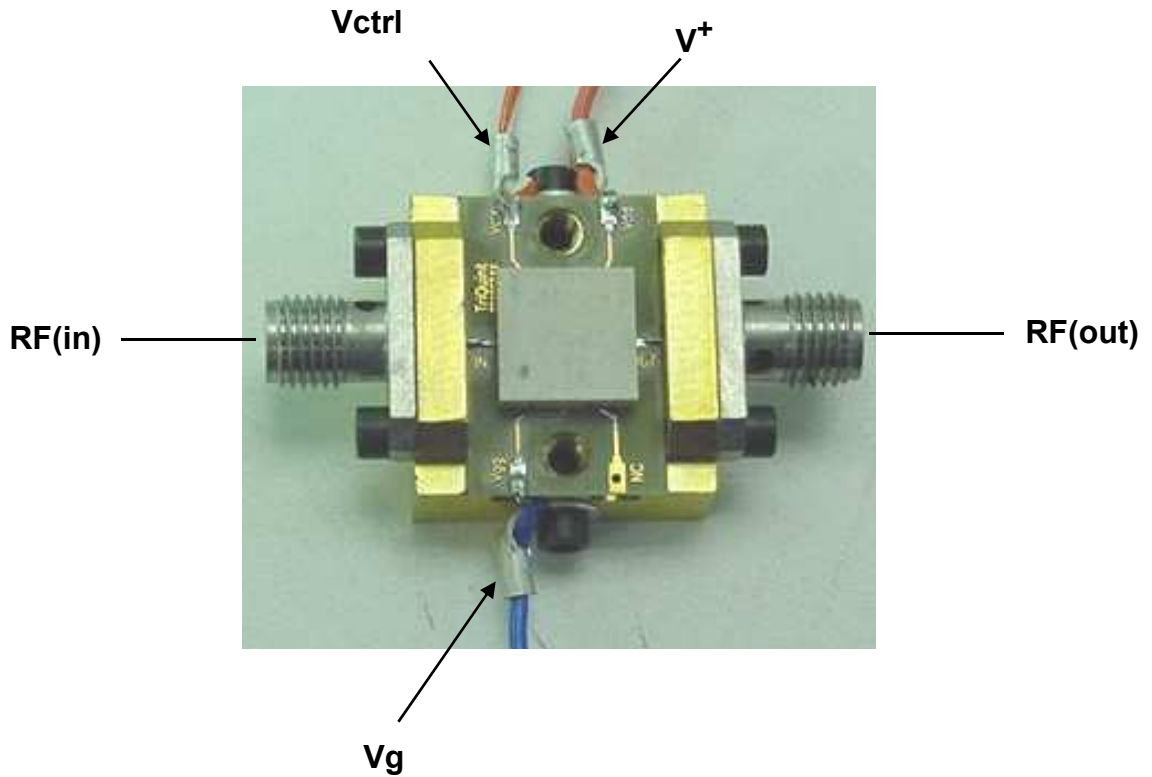
7/ Power Bias Die Probe: V<sub>DT</sub>=8 V, adjust Vg to achieve I<sub>d</sub> = 175 mA+/-5%, V<sub>ctrl</sub> = 1.5 V

Note: At the die level, drain bias is applied thru the RF output port using a bias tee, voltage is at the DC input to the bias tee.

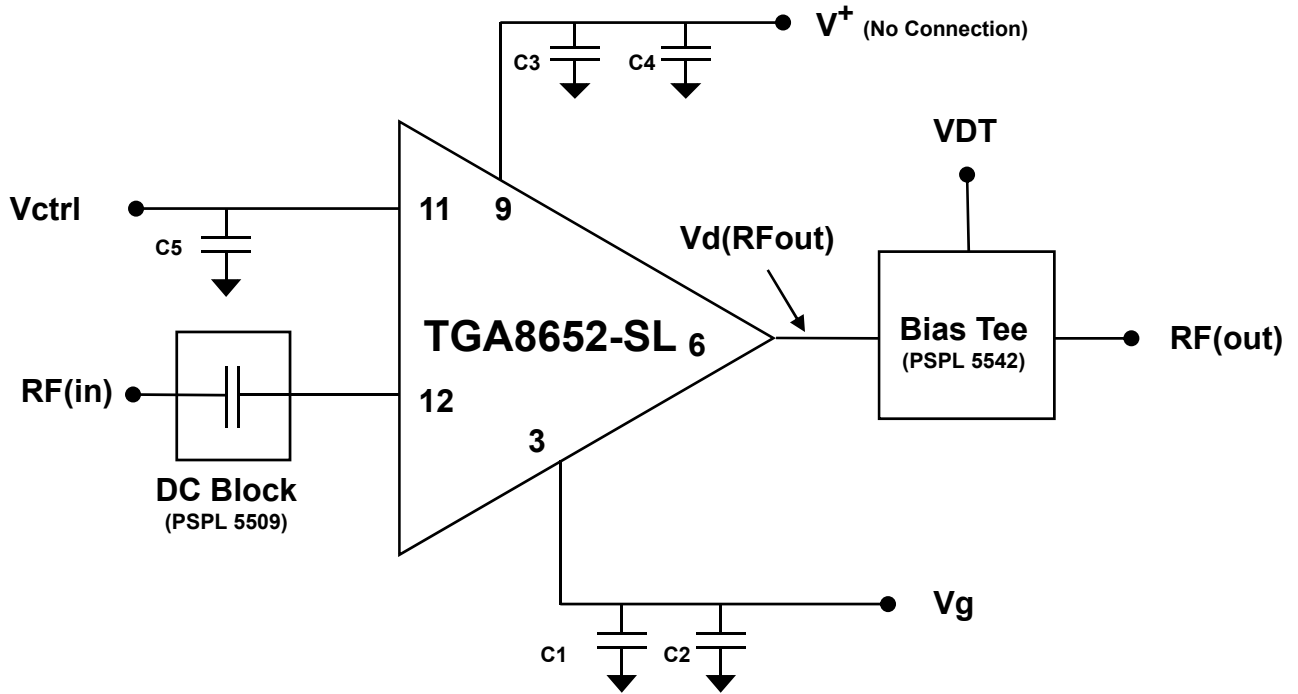
Typical Measured S-parameters



**Demonstration Board**



**Application Circuit**  
**for**  
**4-8V Driver Application**



**Recommended Components:**

DESIGNATOR	DESCRIPTION	MANUFACTURER	PART NUMBER
C1, C3	1uF Capacitor MLC Ceramic	AVX	0603YC105KAT
C2, C4	10 uF Capacitor MLC Ceramic	AVX	0603YC106KAT
C5	0.01 uF Capacitor MLC	AVX	0603YC103KAT

## Bias Procedure for 4-8V Driver Application

### Bias ON

1. Disable the PPG source
2. Set  $V_{dt} = 0V$   $V_{ctrl} = 0V$  and  $V_g = 0V$
3. Set  $V_g = -1.5V$
4. Increase  $V_{dt}$  to 8V observing  $I_d$ .
  - Assure  $I_d = 0mA$
5. Set  $V_{ctrl} = +1.0V$ 
  - $I_d$  should still be 0 mA
6. Make  $V_g$  more positive until  $I_{dd} = 175mA$ .
  - Typical value for  $V_g$  is  $-0.3V$
7. Enable the PPG source
  - $V_{in} = 2V_{pp}$
8. Adjust  $V_{ctrl}$  for  $V_o = 8V_{pp}$
9. Adjust  $V_g$  for 50% crossover

### Bias OFF

1. Disable the output of the PPG
2. Set  $V_{ctrl} = 0V$
3. Set  $V_{dt} = 0V$
4. Set  $V_g = 0V$

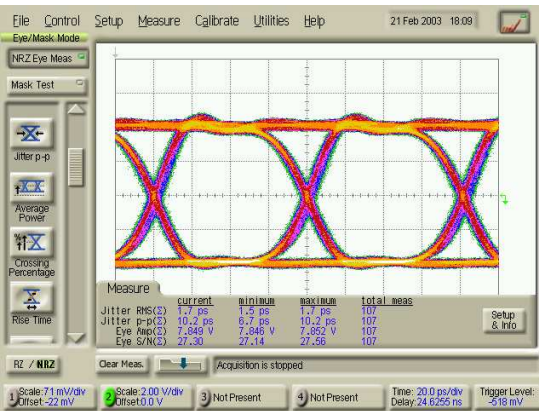
### Notes:

1. Assure  $V_{ctrl}$  never exceeds  $V_d$  during Bias ON and Bias OFF sequences and during normal operation.

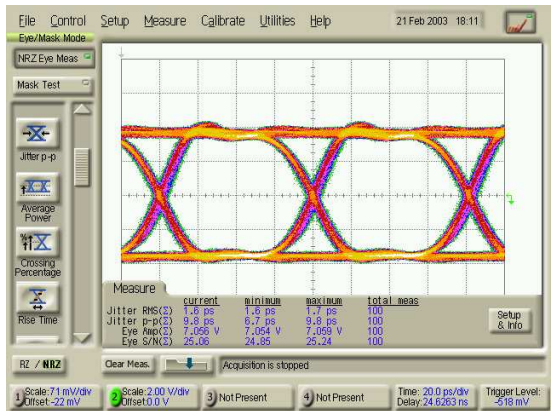


**Typical Measured Performance on Demonstration Board**  
**12.5Gb/s 2<sup>31</sup>-1, Vd(RFout) = 7 V**  
**CPC = 50%**

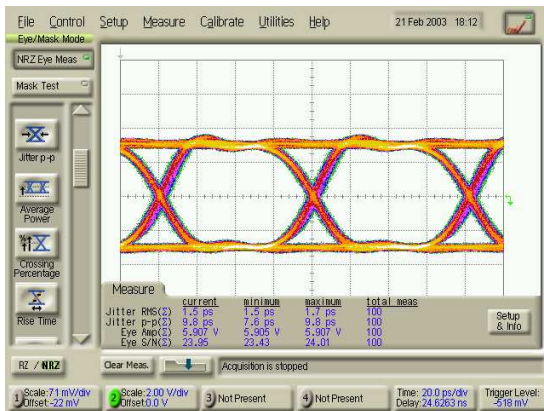
**Vo=8 V**



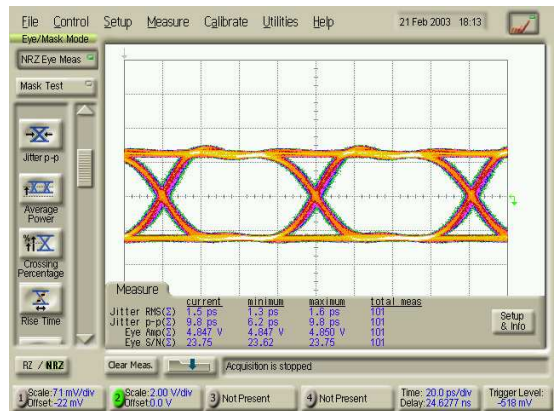
**Vo=7 V**



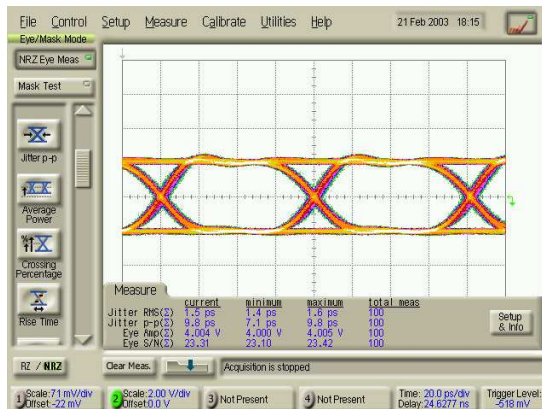
**Vo=6 V**



**Vo=5 V**



**Vo = 4 V**



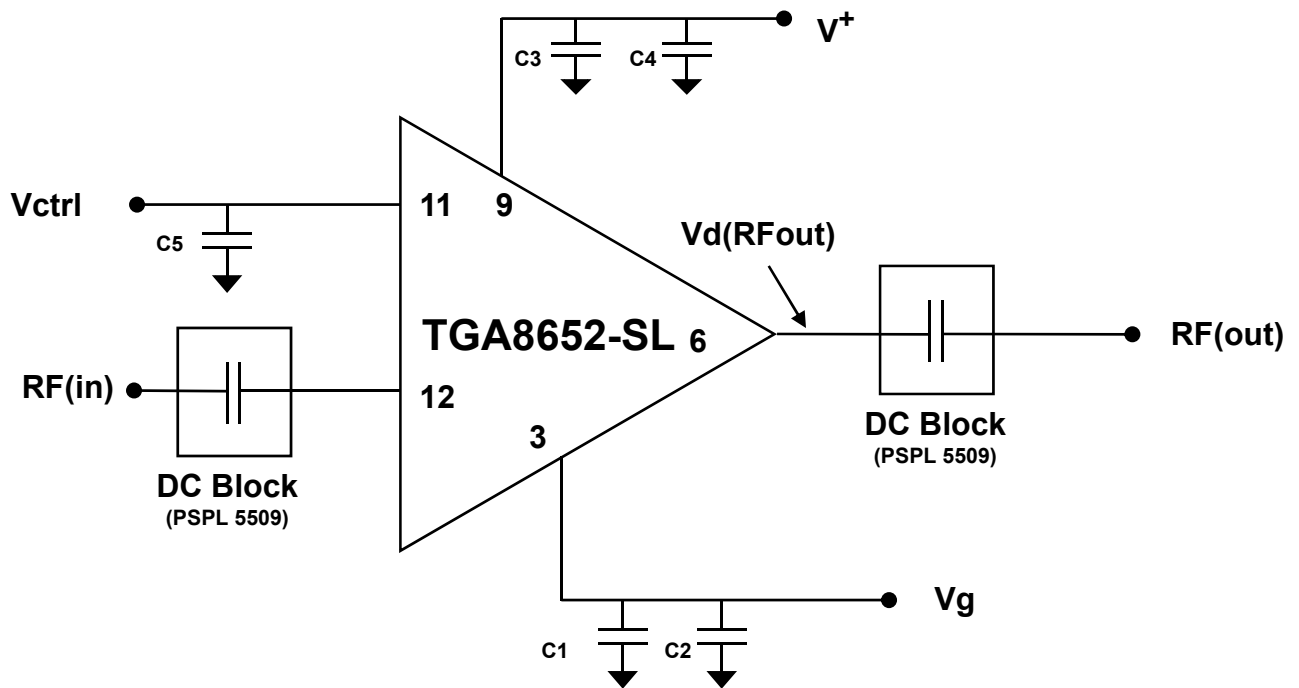
**Typical Bias Conditions**  
**Vd(RFout) = 7 V**

Vo(V)	Vg(V)	Id(mA)	Vctrl
8	-0.23	194	0.87
7	-0.31	173	0.63
6	-0.40	144	0.37
5	-0.48	117	0.16
4	-0.54	97	0.02

Notes:

1. Vd(RFout)=7 V
2. Vin =2 Vpp
3. 50% CPC
4. Actual bias points may be different.

## Application Circuit for Pre-Driver and Receive Application



### Recommended Components:

DESIGNATOR	DESCRIPTION	MANUFACTURER	PART NUMBER
C1, C3	1uF Capacitor MLC Ceramic	AVX	0603YC105KAT
C2, C4	10 uF Capacitor MLC Ceramic	AVX	0603YC106KAT
C5	0.01 uF Capacitor MLC	AVX	0603YC103KAT

## Bias Procedure for Pre-Driver and Receive Application

### Bias ON

1. Disable the PPG source
2. Set  $V^+ = 0$  V,  $V_{ctrl} = 0$  V and  $V_g = 0$  V
3. Set  $V_g = -1.5$  V, Set  $V_{ctrl} = -0.1$  V
4. Increase  $V^+$  to 8 V observing  $I_d$ .
  - Assure  $I_d = 0$  mA
5. Make  $V_g$  more positive until  $I_{dd} = 70$  mA.
  - Typical value for  $V_g$  is  $-0.5$  V
7. Enable the PPG source
  - Set  $V_{in} = 500$  mV (amplitude)

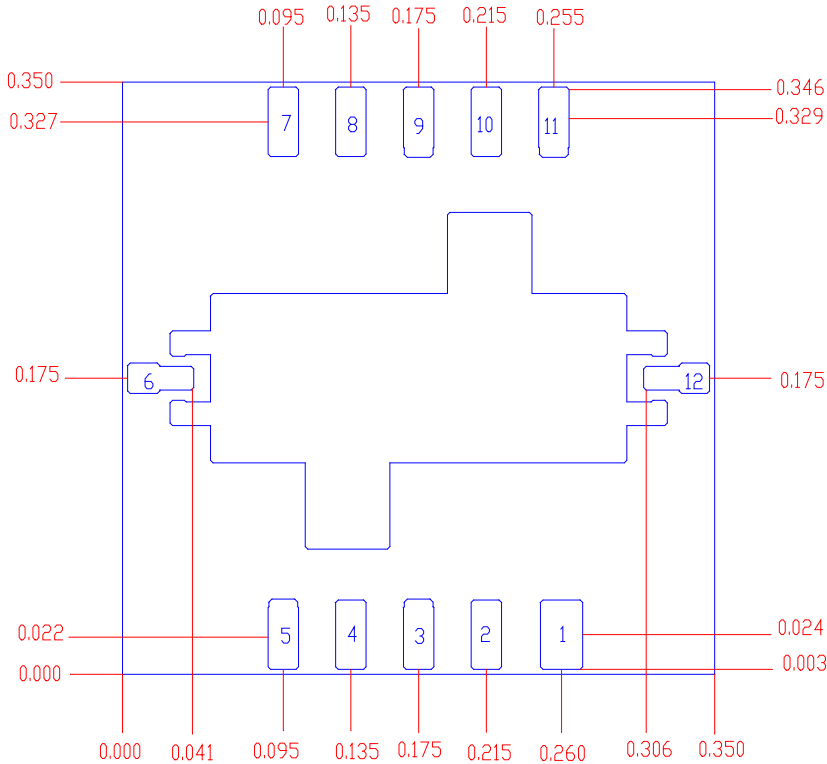
### Bias OFF

1. Disable the output of the PPG
2. Set  $V_{ctrl} = 0$  V
3. Set  $V_{dt} = 0$  V
4. Set  $V_g = 0$  V

### Notes:

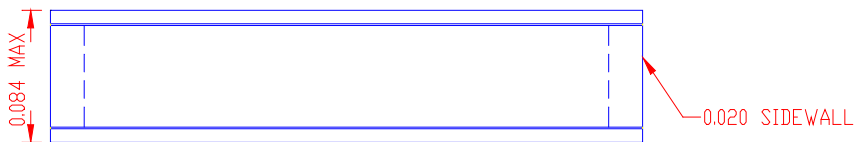
1. Assure  $V_{ctrl}$  never exceeds  $V_d$  during Bias ON and Bias OFF sequences and during normal operation.

**Mechanical Drawing**



<u>PIN</u>	<u>FUNCTION</u>	<u>PIN</u>	<u>FUNCTION</u>
1	NC	7	NC
2	NC	8	NC
3	Vg (0.018 x 0.041)	9	V+ (0.018 x 0.041)
4	NC	10	NC
5	NC	11	Vctrl (0.018 x 0.041)
6	OUT (0.039 x 0.018)	12	IN (0.039 x 0.018)

LID



**Notes:**

- Dimensions: Inches. Tolerance: Length and Width: +/- .003 inches. Height +/- .006 inches. Adjacent pad to pad spacing: +/- .0002 inches. Pad Size: +/- .001 inches.
- Surface Mount Interface:  
Material: RO4003 (thickness=.008 inches), 1/2oz copper (thickness=.0007 inches)  
Plating Finish: 100-350 microinches nickel underplate, with 5-10 microinches flash gold overplate.

## Recommended Surface Mount Package Assembly

Proper ESD precautions must be followed while handling packages.

Clean the board with acetone. Rinse with alcohol. Allow the circuit to fully dry.

TriQuint recommends using a conductive solder paste for attachment. Follow solder paste and reflow oven vendors' recommendations when developing a solder reflow profile. Typical solder reflow profiles are listed in the table below.

Hand soldering is not recommended. Solder paste can be applied using a stencil printer or dot placement. The volume of solder paste depends on PCB and component layout and should be well controlled to ensure consistent mechanical and electrical performance. *This package has little tendency to self-align during reflow.*

### Typical Solder Reflow Profiles

Reflow Profile	SnPb	Pb Free
Ramp-up Rate	3 °C/sec	3 °C/sec
Activation Time and Temperature	60 – 120 sec @ 140 – 160 °C	60 – 180 sec @ 150 – 200 °C
Time above Melting Point	60 – 150 sec	60 – 150 sec
Max Peak Temperature	240 °C	260 °C
Time within 5 °C of Peak Temperature	10 – 20 sec	10 – 20 sec
Ramp-down Rate	4 – 6 °C/sec	4 – 6 °C/sec

### Ordering Information

Part	Package Style
TGA8652-SL	Land Grid Array Surface Mount

***GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.***